

MOSFET – Power, N-Channel

80 V, 2.8 $m\Omega$

NVCR4LS2D8N08M7A

Features

- Typical $R_{DS(on)} = 2.2 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$
- Typical $Q_{g(tot)} = 86 \text{ nC}$ at $V_{GS} = 10 \text{ V}$
- AEC-Q101 Qualified
- RoHS Compliant

DIMENSION (µm)

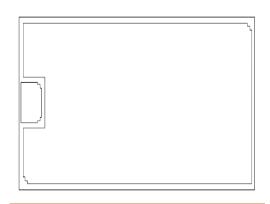
Die Size	4953×2413
Die Size (Sawn)	4933 ±15 × 2393 ±15
Source Attach Area	4748.7 × 2184.6
Gate Attach Area	427.1 × 549.5
Die Thickness	101.6 ±19.1

Gate and Source: AlSiCu

Drain: Ti-NiV-Ag (back side of die)

Passivation: Polyimide Wafer Diameter: 8 inch Wafer Sawn on UV Tape Bad Dice Identified in Inking Gross Die Counts: 2162

The Chip is 100% Probed to Meet the Conditions and Limits Specified at T_J = 25°C.



ORDERING INFORMATION

Device	Package		
NVCR4LS2D8N08M7A	Wafer		
	Sawn on Foil		

RECOMMENDED STORAGE CONDITIONS

Temperature	22 to 28°C		
RH	40 to 66%		

Symbol	Parameter	Condition	Min	Тур	Max	Unit
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80	-	-	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} = 80 V, V _{GS} = 0 V	-	-	1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	-	4.0	V
*R _{DS(on)}	Bare Die Drain to Source On Resistance	I _D = 5 A, V _{GS} = 10 V	-	2.2	2.8	mΩ
V _{SD}	Source to Drain Diode Voltage	I _{SD} = 5 A, V _{GS} = 0 V	-	-	1.2	V
E _{AS}	Single Pulse Drain-to-Source Avalanche Energy	L = 6 mH, I _{AS} = 18.7 A	1049	-	-	mJ

^{*}Accurate R_{DS(on)} test at die level is not feasible for this thin die as limited by the test contact precision attainable in a die form. The max R_{DS(on)} specification is defined from the historical performance of the die in package but is not guaranteed by test in production. The die R_{DS(on)} performance depends on the Source wire/ribbon bonding layout.

1

MOSFET MAXIMUM RATINGS in Reference to the FDBL86366-F085 electrical data in TOLL

(T_J = 25°C unless otherwise noted)

Symbol	Parameter	Ratings	Unit	
V _{DSS}	Drain to Source Voltage	80	V	
V_{GS}	Gate to Source Voltage	±20	V	
I _D	Continuous Drain Current $R_{\theta JC}$ (V_{GS} = 10) (Note 1) T_{C} = 25°C T_{C} = 100°C	221 156	A	
E _{AS}	Single Pulse Avalanche Energy (Note 2)	205	mJ	
P _D	Power Dissipation $R_{\theta JC}$	300	W	
	Derate Above 25°C	2.0	W/°C	
T _J , T _{STG}	Operating and Storage Temperature	-55 to +175	°C	
$R_{ heta JC}$	Thermal Resistance, Junction to Case	0.5	°C/W	
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (Note 3)	43	°C/W	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Current is limited by silicon.
- 2. Starting $T_J = 25^{\circ}C$, L = 0.1 mH, $I_{AS} = 64$ A, $V_{DD} = 80$ V during inductor charging and $V_{DD} = 0$ V during time in avalanche. 3. $R_{\theta JA}$ is the sum of the junction–to–case and case–to–ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in² pad of 2oz copper.

ELECTRICAL CHARACTERISTICS in Reference to the FDBL86366-F085 electrical data in TOLL

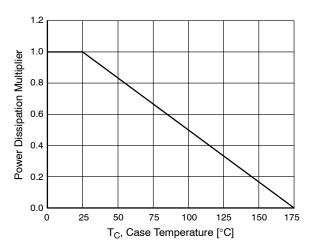
(T_J = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
OFF CHARAC	CTERISTICS						-
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$		80	-	-	V
I _{DSS}	Drain to Source Leakage Current	$V_{DS} = 80 \text{ V},$	T _J = 25°C	_	_	1	μΑ
		$V_{GS} = 0 V$	T _J = 175°C (Note 4)	-	_	1	mA
I _{GSS}	Gate to Source Leakage Current	V _{GS} = ±20 V		_	_	±100	nA
ON CHARACT	TERISTICS						
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D =$	= 250 μA	2.0	3.0	4.0	V
R _{DS(on)}	Drain to Source on Resistance	I _D = 80 A,	$T_J = 25^{\circ}C$	-	2.4	3.0	mΩ
		V _{GS} = 10 V	T _J = 175°C (Note 4)	_	4.9	6.1	mΩ
DYNAMIC CH	ARACTERISTICS						
C _{iss}	Input Capacitance	V_{DS} = 40 V, V_{G}	_S = 0 V, f = 1 MHz	-	6320	_	pF
C _{oss}	Output Capacitance			-	1030	_	pF
C_{rss}	Reverse Transfer Capacitance			-	32	_	pF
R_{g}	Gate Resistance			-	2.1	_	Ω
$Q_{g(ToT)}$	Total Gate Charge			-	86	_	nC
Q _{g(th)}	Threshold Gate Charge			-	12	_	nC
Q_{gs}	Gate to Source Gate Charge	V _{DD} = 64 V, I _D = 80 A		-	30	_	nC
Q_{qd}	Gate to Drain "Miller" Charge			_	18	_	nC
SWITCHING (CHARACTERISTICS						
t _{d(on)}	Turn-On Delay	$V_{DD} = 40 \text{ V}, I_{D} = 80 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		-	30	_	ns
t _r	Rise Time			-	34	-	ns
t _{d(off)}	Turn-Off Delay			-	40	_	ns
t _f	Fall Time			-	17	-	ns
DRAIN-SOUP	RCE DIODE CHARACTERISTIC						
V_{SD}	Source to Drain Diode Voltage	I _{SD} = 80 A, V _{GS}	s = 0 V	_	_	1.25	V
		I _{SD} = 40 A, V _{GS}	s = 0 V	-	_	1.2	V
t _{rr}	Reverse Recovery Time	$I_F = 80 \text{ A}, dI_{SD}/$	dt = 100 A/μs,	-	80		ns
Q_{rr}	Reverse Recovery Charge	V _{DD} = 64 V		_	95	_	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

^{4.} The maximum value is specified by design at T_J = 175°C. Product is not tested to this condition in production.

TYPICAL CHARACTERISTICS



250 Current limited V_{GS} = 10 V by silicon 200 ID, Drain Current [A] 150 100 50 0 25 50 100 125 175 200 75 150 T_C, Case Temperature [°C]

Figure 1. Normalized Power Dissipation vs. Case Temperature

Figure 2. Maximum Continuous Drain Current vs. Case Temperature

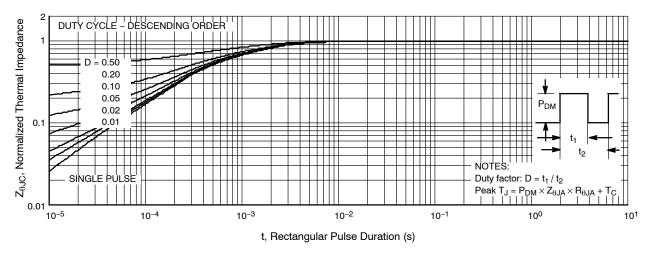


Figure 3. Normalized Maximum Transient Thermal Impedance

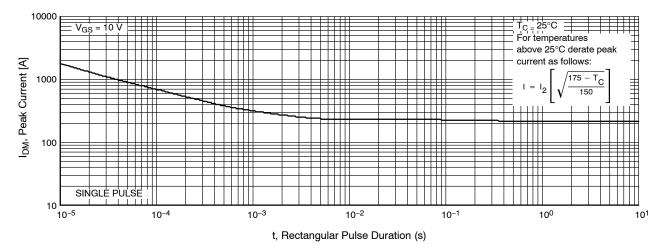


Figure 4. Peak Current Capability

TYPICAL CHARACTERISTICS (continued)

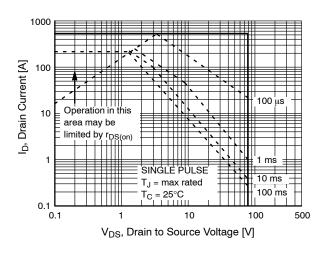


Figure 5. Forward Bias Safe Operating Area

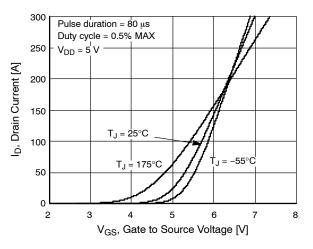


Figure 7. Transfer Characteristics

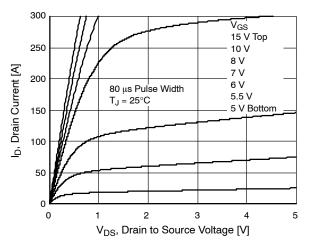
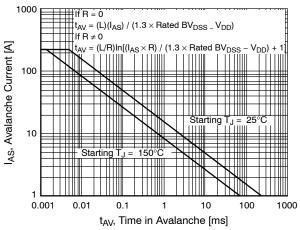


Figure 9. Saturation Characteristics



NOTE: Refer to onsemi Application Notes AN7514 and AN7515.

Figure 6. Unclamped Inductive Switching Capability

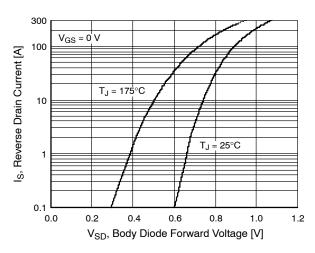


Figure 8. Forward Diode Characteristics

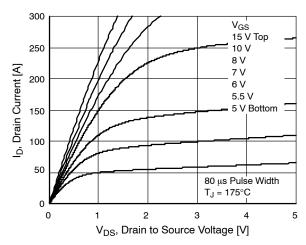


Figure 10. Saturation Characteristics

TYPICAL CHARACTERISTICS (continued)

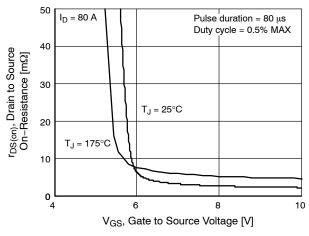


Figure 11. R_{DSON} vs. Gate Voltage

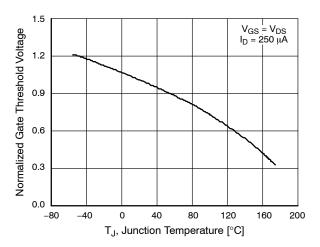


Figure 13. Normalized Gate Threshold Voltage vs. Temperature

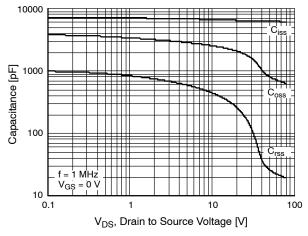


Figure 15. Capacitance vs. Drain to Source Voltage

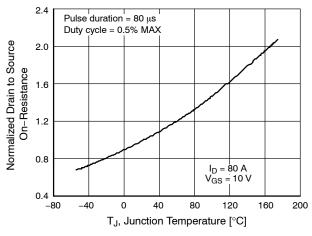


Figure 12. Normalized $R_{\mbox{\footnotesize DSON}}$ vs. Junction Temperature

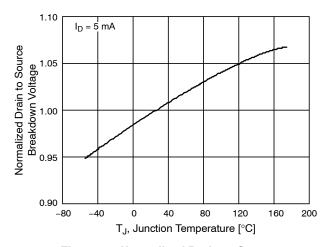


Figure 14. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

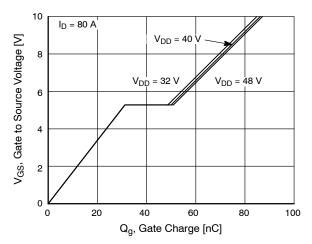


Figure 16. Gate Charge vs. Gate to Source Voltage

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